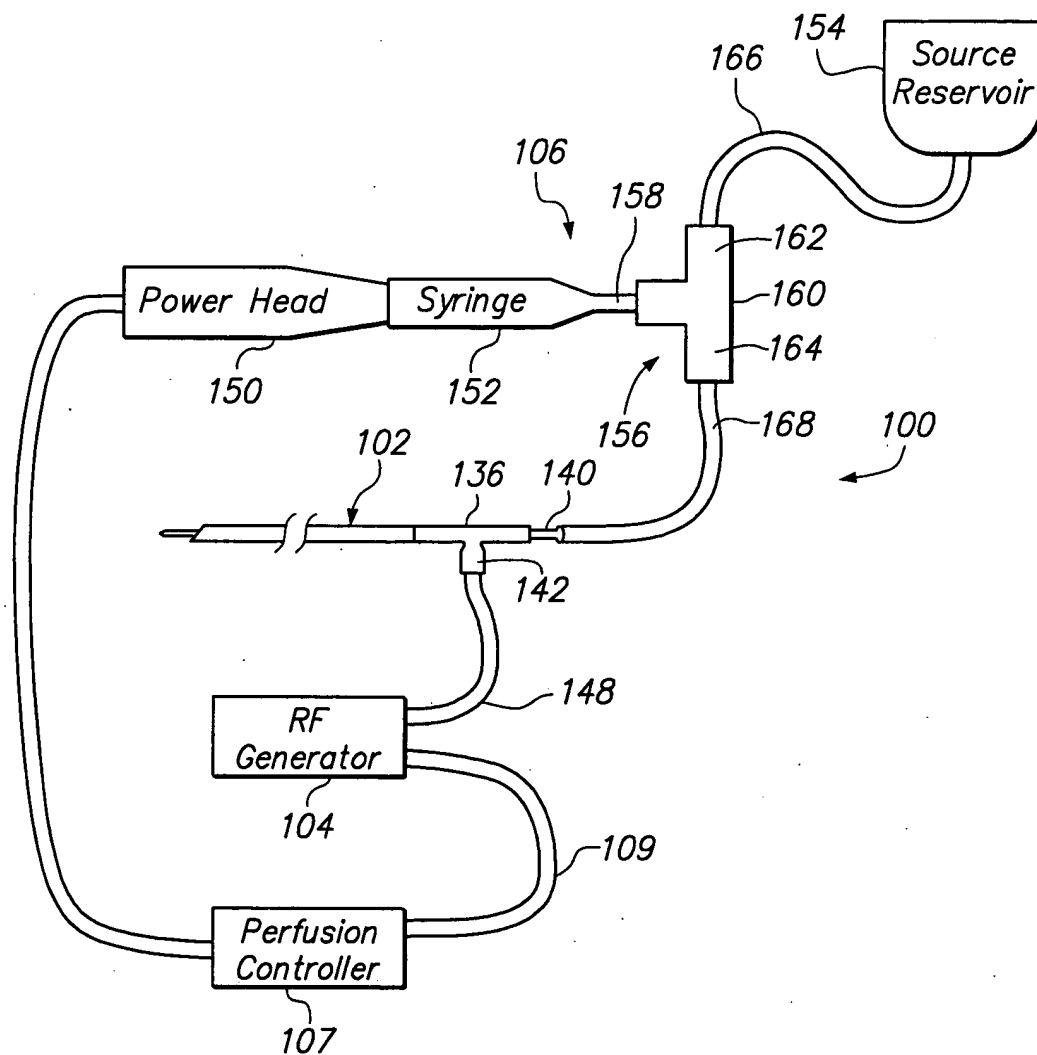




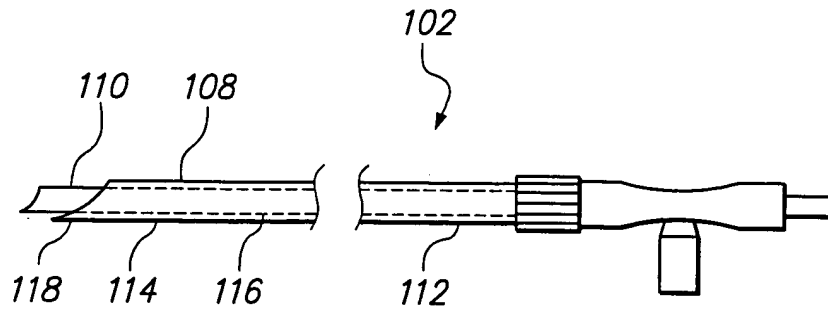
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FIG. 1

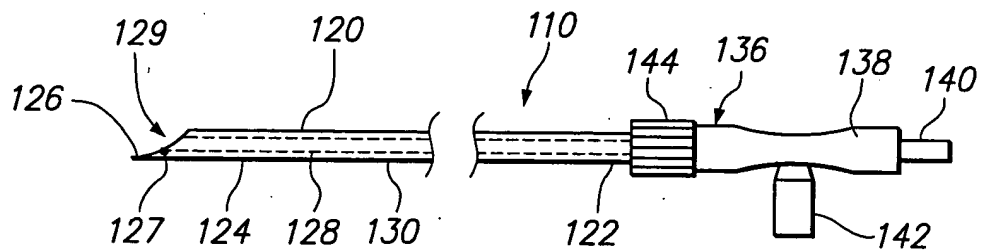


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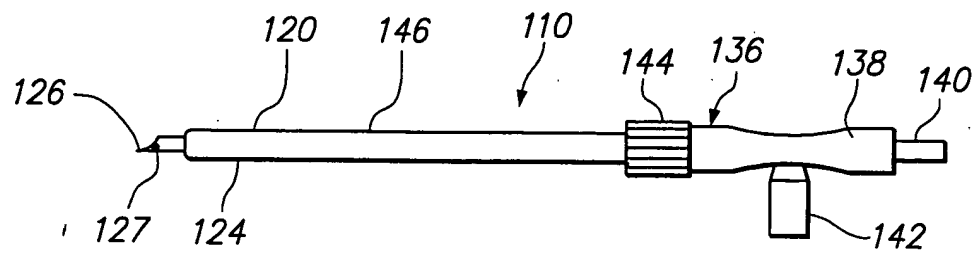
**FIG. 2**



**FIG. 3**



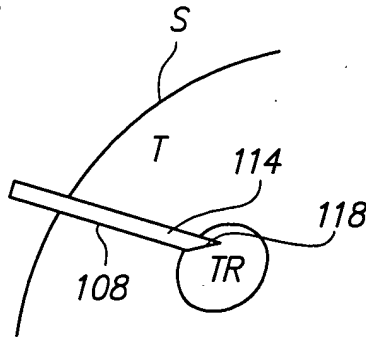
**FIG. 4**



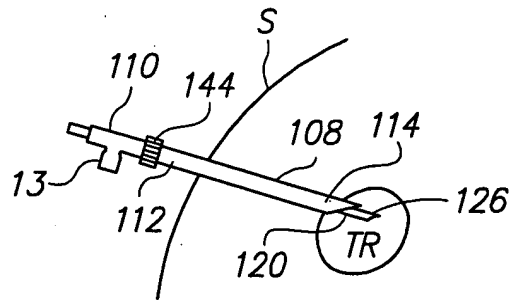


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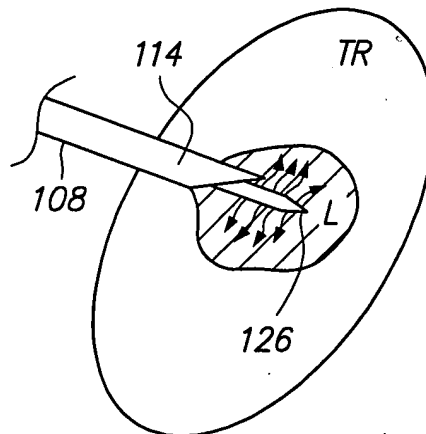
**FIG. 7A**



**FIG. 7B**



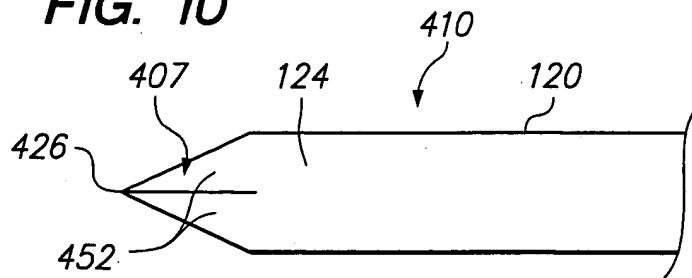
**FIG. 7C**



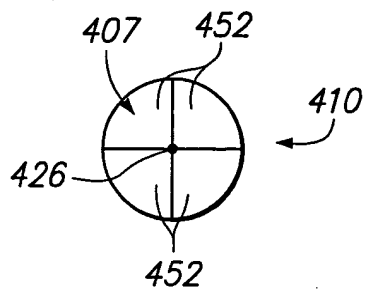
[illegible]

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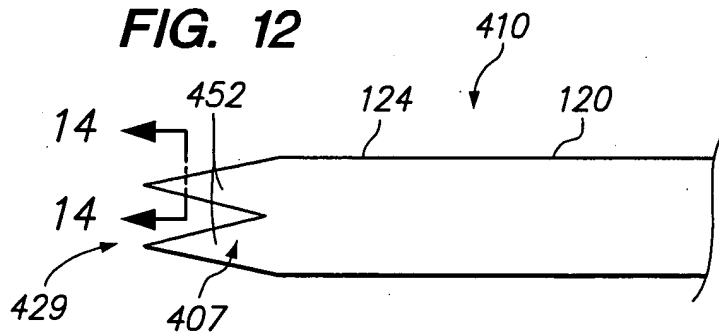
**FIG. 10**



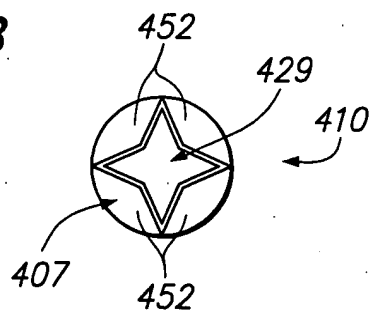
**FIG. 11**



**FIG. 12**



**FIG. 13**

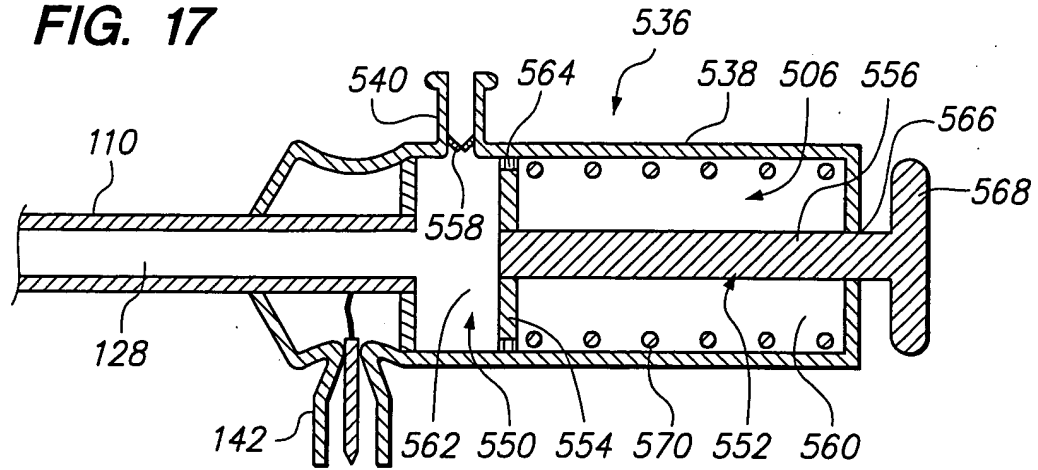


**FIG. 16**

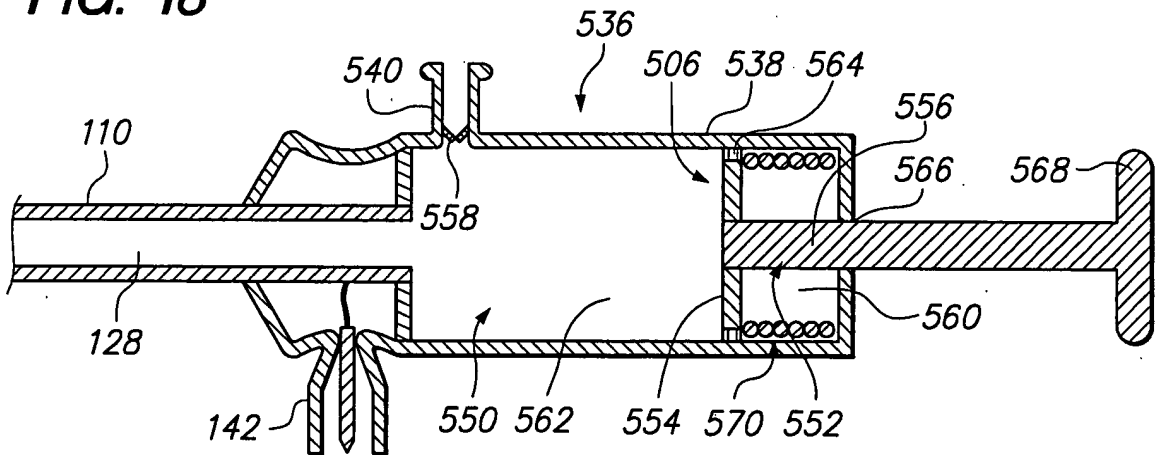
FIG. 16 is a cross-sectional view of a device 410. The device includes a top layer 452, a middle layer 436, and a bottom layer 438. A vertical probe 446 with a T-shaped handle is positioned above a central opening 440 in the top layer 452. The probe's tip is at the opening. Below the top layer is a middle layer 436 and a bottom layer 438. A dashed line 406 shows a curved path within the bottom layer. On the left, a horizontal structure 110 is shown with a layer 128 and a vertical support 142. An arrow 458 points to the interface between the top and middle layers. An arrow 450 points to the bottom layer. The entire assembly is labeled 410.

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**FIG. 17**



**FIG. 18**



**FIG. 19**

